

Semiconductor Physics and testing analysis(Chinese Edition)

By TAN CHANG LONG ZHU BIAN

paperback. Book Condition: New. Ship out in 2 business day, And Fast shipping, Free Tracking number will be provided after the shipment.Paperback. Pub Date :2012-08-01 Pages: 152 Publisher: Basic information of Harbin Institute of Technology Press title: semiconductor physics test analysis Original Price: \$ 20 Author: Tan Changlong editor of Press: Harbin Institute of Technology Press Publication Date: 2012 -8-1ISBN: 9787560336480 word count: 220.000 yards: 152 Revision: 1 Binding: Paperback: 16 product size and weight: Editor's Summary Electronics and Communication Engineering Series: semiconductor physics test analysis more fully describes the The basics of semiconductor physics test analysis. Mainly includes: the basic nature of the semiconductor; semiconductor impurity and defect levels. and silicon dislocations and stacking fault observed; statistical distribution of the carriers in the equilibrium state semiconductor. the impurity concentration and its distribution of the measurement technique; carrier oscillator in the law of motion under the electric field. and the Hall coefficient and conductivity measurement methods; law of motion of nonequilibrium carriers and their generation and recombination mechanisms. minority carrier lifetime measurement; pn junction formation process its electrical properties. pn junction barrier capacitance measurements. Electronics and Communication Engineering Series: semiconductor physics. science and engineering as undergraduate colleges microelectronics, electronic science.

Reviews

I just started out looking at this ebook. This can be for those who statte there had not been a worthy of reading through. You can expect to like the way the blogger publish this ebook. -- Dr. Freddie Greenholt Jr.

Definitely among the finest book We have at any time read. Better then never, though i am quite late in start reading this one. Your lifestyle period will likely be transform once you total reading this article book. -- Florence Batz IV